

# SN54ABT162827, SN74ABT162827 20-BIT BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

SCBS248B – JULY 1993 – REVISED DECEMBER 1994

- Output Ports Have Equivalent 25- $\Omega$  Series Resistors, So No External Resistors Are Required
- Members of the Texas Instruments *Widebus*™ Family
- State-of-the-Art *EPIC-II B*™ BiCMOS Design Significantly Reduces Power Dissipation
- Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17
- Typical  $V_{OLP}$  (Output Ground Bounce) < 1 V at  $V_{CC} = 5$  V,  $T_A = 25^\circ\text{C}$
- Distributed  $V_{CC}$  and GND Pin Configuration Minimizes High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB Layout
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings

## description

The 'ABT162827 are noninverting 20-bit buffers composed of two 10-bit buffers with separate output-enable signals. For either 10-bit buffer, the two output-enable ( $1\overline{OE}1$  and  $1\overline{OE}2$  or  $2\overline{OE}1$  and  $2\overline{OE}2$ ) inputs must both be low for the corresponding Y outputs to be active. If either output-enable input is high, the outputs of that 10-bit buffer are in the high-impedance state.

The outputs, which are designed to source or sink up to 12 mA, include 25- $\Omega$  series resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down,  $\overline{OE}$  inputs should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74ABT162827 is available in TI's shrink small-outline package (DL), which provides twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

The SN54ABT162827 is characterized for operation over the full military temperature range of  $-55^\circ\text{C}$  to  $125^\circ\text{C}$ . The SN74ABT162827 is characterized for operation from  $-40^\circ\text{C}$  to  $85^\circ\text{C}$ .

## SN54ABT162827 . . . WD PACKAGE SN74ABT162827 . . . DGG OR DL PACKAGE (TOP VIEW)

$1\overline{OE}1$	1	56	$1\overline{OE}2$
1Y1	2	55	1A1
1Y2	3	54	1A2
GND	4	53	GND
1Y3	5	52	1A3
1Y4	6	51	1A4
$V_{CC}$	7	50	$V_{CC}$
1Y5	8	49	1A5
1Y6	9	48	1A6
1Y7	10	47	1A7
GND	11	46	GND
1Y8	12	45	1A8
1Y9	13	44	1A9
1Y10	14	43	1A10
2Y1	15	42	2A1
2Y2	16	41	2A2
2Y3	17	40	2A3
GND	18	39	GND
2Y4	19	38	2A4
2Y5	20	37	2A5
2Y6	21	36	2A6
$V_{CC}$	22	35	$V_{CC}$
2Y7	23	34	2A7
2Y8	24	33	2A8
GND	25	32	GND
2Y9	26	31	2A9
2Y10	27	30	2A10
$2\overline{OE}1$	28	29	$2\overline{OE}2$

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# SN54ABT162827, SN74ABT162827

## 20-BIT BUFFERS/DRIVERS

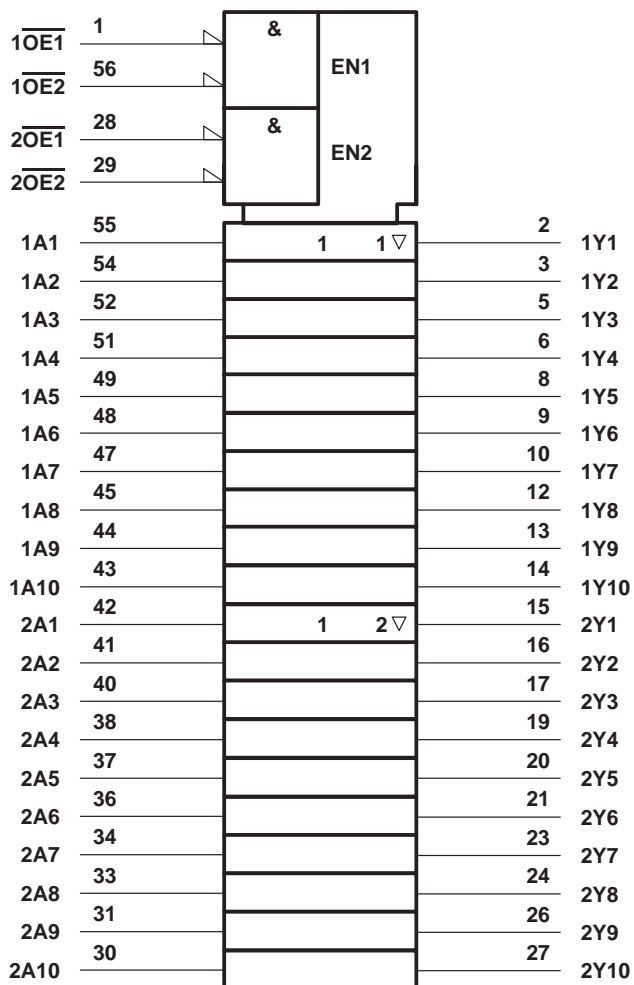
### WITH 3-STATE OUTPUTS

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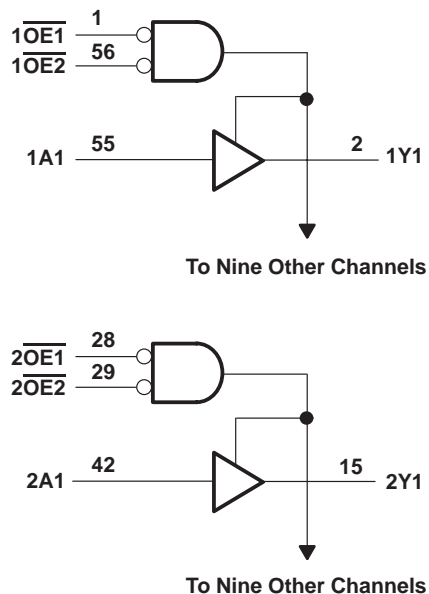
FUNCTION TABLE  
(each 10-bit buffer)

INPUTS			OUTPUT Y
OE1	OE2	A	
L	L	L	L
L	L	H	H
H	X	X	Z
X	H	X	Z

#### logic symbol†



#### logic diagram (positive logic)



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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## 20-BIT BUFFERS/DRIVERS

### WITH 3-STATE OUTPUTS

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#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage range, $V_{CC}$	–0.5 V to 7 V
Input voltage range, $V_I$ (see Note 1)	–0.5 V to 7 V
Voltage range applied to any output in the high state or power-off state, $V_O$	–0.5 V to 5.5 V
Current into any output in the low state, $I_O$	30 mA
Input clamp current, $I_{IK}$ ( $V_I < 0$ )	–18 mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ )	–50 mA
Maximum power dissipation at $T_A = 55^\circ\text{C}$ (in still air) (see Note 2):	
DGG package	1 W
DL package	1.4 W
Operating free-air temperature range, $T_A$ : SN54ABT162827	–55°C to 125°C
SN74ABT162827	–40°C to 85°C
Storage temperature range	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.  
2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils. For more information, refer to the *Package Thermal Considerations* application note in the 1994 *ABT Advanced BiCMOS Technology Data Book*, literature number SCBD002B.

#### recommended operating conditions (see Note 3)

		SN54ABT162827		SN74ABT162827		UNIT	
		MIN	MAX	MIN	MAX		
V <sub>CC</sub>	Supply voltage		4.5	5.5	4.5	5.5	V
V <sub>IH</sub>	High-level input voltage		2		2		V
V <sub>IL</sub>	Low-level input voltage			0.8		0.8	V
V <sub>I</sub>	Input voltage		0	V <sub>CC</sub>	0	V <sub>CC</sub>	V
I <sub>OH</sub>	High-level output current			−12		−12	mA
I <sub>OL</sub>	Low-level output current			12		12	mA
Δt/ΔV	Input transition rise or fall rate	Control inputs		9		9	ns/V
		Data inputs		10		10	
Δt/ΔV <sub>CC</sub>	Power-up ramp rate		200		200		μs/V
T <sub>A</sub>	Operating free-air temperature		−55	125	−40	85	°C

NOTE 3: Unused or floating inputs must be held high or low.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	T <sub>A</sub> = 25°C			SN54ABT162827		SN74ABT162827		UNIT
		MIN	TYP†	MAX	MIN	MAX	MIN	MAX	
V <sub>IK</sub>	V <sub>CC</sub> = 4.5 V, I <sub>I</sub> = –18 mA			–1.2		–1.2		–1.2	V
V <sub>OH</sub>	V <sub>CC</sub> = 4.5 V, I <sub>OH</sub> = –1 mA	2.5			2.5		2.5		V
	V <sub>CC</sub> = 5 V, I <sub>OH</sub> = –1 mA	3			3		3		
	V <sub>CC</sub> = 4.5 V	I <sub>OH</sub> = –3 mA	2.4		2.4		2.4		
		I <sub>OH</sub> = –12 mA	2		2		2		
V <sub>OL</sub>	V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 8 mA	0.4	0.8	0.8		0.65		V
		I <sub>OL</sub> = 12 mA					0.8		
I <sub>I</sub>	V <sub>CC</sub> = 0 to 5.5 V, V <sub>I</sub> = V <sub>CC</sub> or GND			±1		±1		±1	μA
I <sub>OZPU</sub>	V <sub>CC</sub> = 0 to 2.1 V, V <sub>O</sub> = 0.5 V to 2.7 V, $\overline{OE} = X$			±50		±50		±50	μA
I <sub>OZPD</sub>	V <sub>CC</sub> = 2.1 V to 0, V <sub>O</sub> = 0.5 V to 2.7 V, $\overline{OE} = X$			±50		±50		±50	μA
I <sub>OZH</sub> ‡	V <sub>CC</sub> = 2.1 V to 5.5 V, V <sub>O</sub> = 2.7 V, $\overline{OE} \geq 2$ V			10		10		10	μA
I <sub>OZL</sub> ‡	V <sub>CC</sub> = 2.1 V to 5.5 V, V <sub>O</sub> = 0.5 V, $\overline{OE} \geq 2$ V			–10		–10		–10	μA
I <sub>off</sub>	V <sub>CC</sub> = 0, V <sub>I</sub> or V <sub>O</sub> ≤ 4.5 V			±100				±100	μA
I <sub>CEX</sub>	Outputs high V <sub>CC</sub> = 5.5 V, V <sub>O</sub> = 5.5 V			50		50		50	μA
I <sub>O</sub> §	V <sub>CC</sub> = 5.5 V, V <sub>O</sub> = 2.5 V	–25	–75	–100	–25	–100	–25	–100	mA
I <sub>CC</sub>	Outputs high			2		2		2	mA
	Outputs low			32		32		32	
	Outputs disabled			2		2		2	
ΔI <sub>CC</sub> ¶	Data inputs	V <sub>CC</sub> = 5.5 V, One input at 3.4 V, Other inputs at V <sub>CC</sub> or GND	Outputs enabled	1		1.5		1	mA
			Outputs disabled	0.05		1		0.05	
	Control inputs	V <sub>CC</sub> = 5.5 V, One input at 3.4 V, Other inputs at V <sub>CC</sub> or GND		1.5		1.5		1.5	
C <sub>i</sub>	V <sub>I</sub> = 2.5 V or 0.5 V			3.5					pF
C <sub>O</sub>	V <sub>O</sub> = 2.5 V or 0.5 V			8					pF

† All typical values are at V<sub>CC</sub> = 5 V.

‡ The parameters I<sub>OZH</sub> and I<sub>OZL</sub> include the input leakage current.

§ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

¶ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V<sub>CC</sub> or GND.

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switching characteristics over recommended ranges of supply voltage and operating free-air temperature,  $C_L = 50$  pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 5$ V, $T_A = 25^\circ\text{C}$			SN54ABT162827		SN74ABT162827		UNIT
			MIN	TYP†	MAX	MIN	MAX	MIN	MAX	
$t_{PLH}$	A	Y	1	2.1	3.6	1	4.1	1	3.9	ns
$t_{PHL}$			1.1	2.8	4.2	1.1	5	1.1	4.7	
$t_{PZH}$	$\overline{OE}$	Y	1.5	3.4	6.3	1.5	7.2	1.5	6.9	ns
$t_{PZL}$			1.6	3.5	7.3	1.6	6.6	1.6	6.3	
$t_{PHZ}$	$\overline{OE}$	Y	2.1	4.1	6.5	2.1	6.8	2.1	6.6	ns
$t_{PLZ}$			1.5	3.5	5.9	1.5	7.3	1.5	6.3	

† All typical values are at  $V_{CC} = 5$  V.

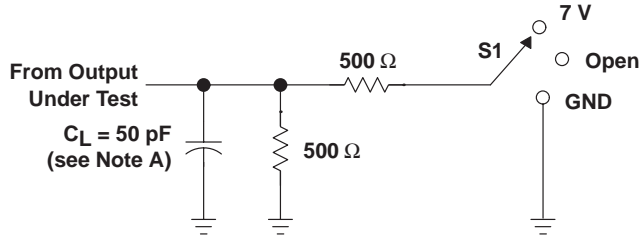
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### WITH 3-STATE OUTPUTS

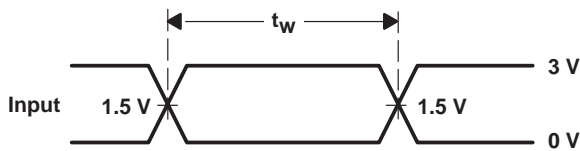
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#### PARAMETER MEASUREMENT INFORMATION

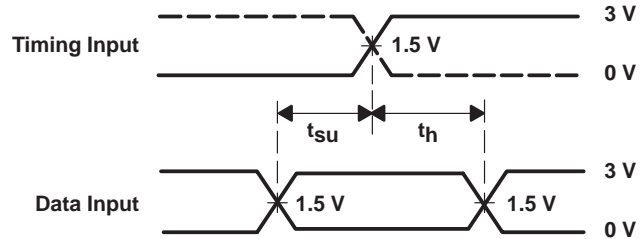


LOAD CIRCUIT FOR OUTPUTS

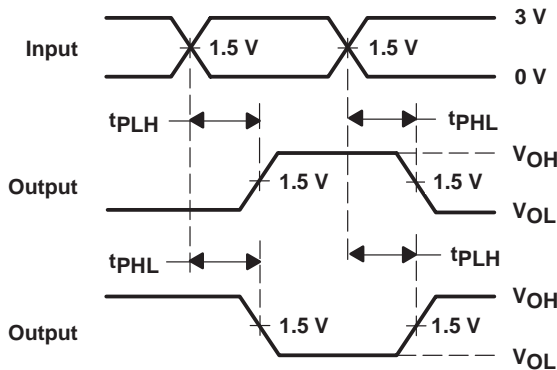
TEST	S1
$t_{PLH}/t_{PHL}$	Open
$t_{PLZ}/t_{PZL}$	7 V
$t_{PHZ}/t_{PZH}$	Open



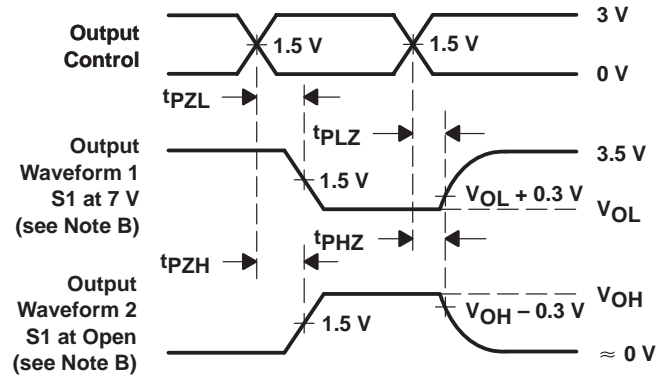
VOLTAGE WAVEFORMS  
PULSE DURATION



VOLTAGE WAVEFORMS  
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS  
PROPAGATION DELAY TIMES  
INVERTING AND NONINVERTING OUTPUTS



VOLTAGE WAVEFORMS  
ENABLE AND DISABLE TIMES  
LOW- AND HIGH-LEVEL ENABLING

- NOTES: A.  $C_L$  includes probe and jig capacitance.  
 B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.  
 C. All input pulses are supplied by generators having the following characteristics:  $PRR \leq 10$  MHz,  $Z_O = 50 \Omega$ ,  $t_r \leq 2.5$  ns,  $t_f \leq 2.5$  ns.  
 D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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